



제 30회 한국반도체학술대회

The 30th Korean Conference on Semiconductors

2023년 2월 13일(월)~ 15일(수) | 강원도 하이원리조트(그랜드호텔 컨벤션타워)

2023년 2월 15일(수), 16:00-17:45

Room L (다이아몬드 II, 6층)

G. Device & Process Modeling, Simulation and Reliability 분과

[WL3-G] Thin Film and Memory Devices

좌장: 나현철 상무(DB 하이텍), 홍성민 교수(GIST)

WL3-G-1 16:00-16:15	On the Scalability of the Amorphous InGaZnO Field-effect Transistors Compared with Silicon-on-insulator Field-effect Transistors Ho Jung Lee, Donguk Kim, Jong-Ho Bae, Sung-Jin Choi, Dong Myong Kim, and Dae Hwan Kim <i>School of Electrical Engineering, Kookmin University</i>
WL3-G-2 16:15-16:30	Characterization of Photovoltaic and Photoconductive Responses in Amorphous Oxide Semiconductor Thin-Film Transistors Seung Hyeop Han, Han Bin Yoo, Haesung Kim, Jihee Ryu, Ju Young Park, Jong-Ho Bae, Sung-Jin Choi, Dae Hwan Kim, and Dong Myong Kim <i>Kookmin University</i>
WL3-G-3 16:30-16:45	Characterization of Lateral Trap Distribution in AOS TFTs through Capacitance-Voltage Technique Combined with Extended Channel Conduction Factor Han Bin Yoo, Haesung Kim, Jihee Ryu, Ju Young Park, Seung Hyeop Han, Hyo-In Yang, Jong-Ho Bae, Sung-Jin Choi, Dae Hwan Kim, and Dong Myong Kim <i>Kookmin University</i>
WL3-G-4 16:45-17:00	Development of In-House Device Simulator for NAND Flash Memories Sang-Mok Jeong and Sung-Min Hong <i>School of Electrical Engineering and Computer Science, GIST</i>
WL3-G-5 17:00-17:15	Retention Characteristics with Cross-Temperature Effects in 3-D NAND Flash Memory Ukju An, Gilsang Yoon, Donghyun Go, Jounghun Park, Donghwi Kim, Jongwoo Kim, and Jeong-Soo Lee <i>Department of Electrical Engineering, POSTECH</i>
WL3-G-6 17:15-17:30	Statistical Distribution of DRAM Retention Time due to Geometric Fluctuation Geonho Park and Sung-Min Hong <i>School of Electrical Engineering and Computer Science, GIST</i>
WL3-G-7 17:30-17:45	Fault-tolerant RRAM-Based Convolutional Kernel Using Hybrid Precision Quantization for Image Processing Seonuk Jeon ¹ , Eunryeong Hong ² , Heebum Kang ² , Hyun Wook Kim ² , Nayeon Kim ¹ , and Jiyong Woo ^{1,2} <i>¹School of Electronics Engineering, Kyungpook National University, ²School of Electronic and Electrical Engineering, Kyungpook National University</i>